

RoHS

## WFF830-VB Datasheet

# N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	650			
R <sub>DS(on)</sub> at 25 °C (Ω)	$V_{GS} = 10 V$	1.1		
Q <sub>g</sub> max. (nC)	25			
Q <sub>gs</sub> (nC)	2.0			
Q <sub>gd</sub> (nC)	2.7			
Configuration	Single			

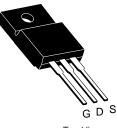
### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>q</sub>)
- Avalanche energy rated (UIS)

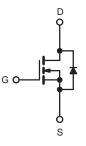
#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
- Fluorescent ballast lighting
- Industrial

TO-220 FULLPAK



Top View



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T $_{\rm C}$ :	= 25 °C, unl	less otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	650	N/	
Gate-Source Voltage			V <sub>GS</sub>	± 30	V	
Continuous Drain Current (T <sub>1</sub> = 150 °C)	V <sub>GS</sub> at 10 V	$T_C = 25 \text{ °C}$ $T_C = 100 \text{ °C}$	- I <sub>D</sub> -	7.0	A	
Continuous Drain Current $(1_j = 150 \text{ C})$	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		5.6		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	28		
Linear Derating Factor				1.67/1.5/0.3	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	86	mJ	
Maximum Power Dissipation			PD	83/83/31	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope $T_J = 125 \text{ °C}$		a\\//alt	50	V/ns		
Reverse Diode dV/dt <sup>d</sup>			dV/dt			4.5
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for	10 s		300	°C	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. V<sub>DD</sub> = 50 V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 3.5 A.

c. 1.6 mm from case. d.  $I_{SD} \le I_D$ , dl/dt = 100 A/µs, starting  $T_J = 25$  °C.



THERMAL RESISTANCE RAT	INGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	63	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.6	0/11

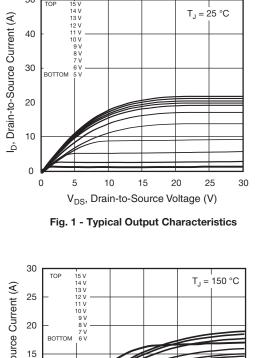
PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT
Static				•	•	•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	= 0 V, I <sub>D</sub> = 250 μA	650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μΑ	2.5	-	5	V
		,	V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Gate-Source Leakage	I <sub>GSS</sub>	,	$V_{GS} = \pm 30 \text{ V}$	-	-	± 1	μA
		V <sub>DS</sub> =	= 650 V, V <sub>GS</sub> = 0 V	-	-	1	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 520 V	∕, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 V$	$I_D = 4 A$	-	1.1	-	Ω
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub>	= 30 V, I <sub>D</sub> = 4 A	-	16	-	S
Dynamic		•					
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,	-	860	-	
Output Capacitance	C <sub>oss</sub>	-	$V_{\rm GS} = 0.0$ V, $V_{\rm DS} = 100$ V,	-	120	-	1
Reverse Transfer Capacitance	C <sub>rss</sub>	-	f = 1 MHz	-	15	-	1
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>			-	45	-	pF
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>	- V <sub>DS</sub> = 0 V	/ to 520 V, V <sub>GS</sub> = 0 V	-	62	-	
Total Gate Charge	Qg			-	25		
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 V$	$I_D = 4 \text{ A}, V_{DS} = 520 \text{ V}$	-	2.0	-	nC
Gate-Drain Charge	Q <sub>gd</sub>			-	2.7	-	]
Turn-On Delay Time	t <sub>d(on)</sub>			-	25	-	
Rise Time	t <sub>r</sub>	$V_{DD} = 520$ V, $I_D = 4$ A, V <sub>GS</sub> = 10 V, R <sub>q</sub> = 9.1 Ω		-	55	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>			-	70	-	
Fall Time	t <sub>f</sub>			-	40	-	1
Gate Input Resistance	R <sub>g</sub>	f = 1	MHz, open drain	-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET syml showing the		-	-	7	
Pulsed Diode Forward Current	I <sub>SM</sub>	integral revers p - n junction		-	-	18	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °	C, I <sub>S</sub> = 4 A, V <sub>GS</sub> = 0 V	-	-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>			-	190	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>		5 °C, I <sub>F</sub> = I <sub>S</sub> = 4 A, I00 A/μs, V <sub>B</sub> = 400 V	-	2.3	-	μC
Reverse Recovery Current	I <sub>RRM</sub>	ui/dt =	$100 \text{ Pv} \mu\text{s}, \text{ v}_{\text{R}} = 400 \text{ v}$	-	10	-	A

#### Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .

50

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## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

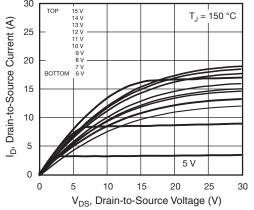


Fig. 2 - Typical Output Characteristics

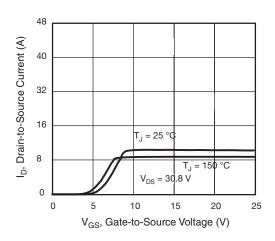


Fig. 3 - Typical Transfer Characteristics

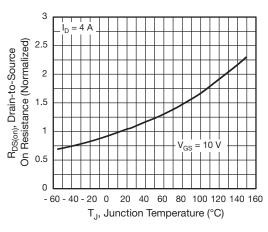


Fig. 4 - Normalized On-Resistance vs. Temperature

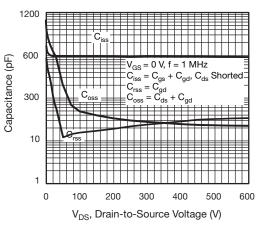


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



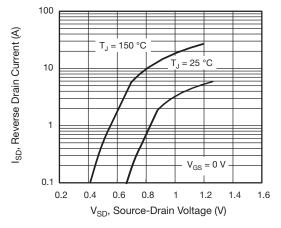


Fig. 7 - Typical Source-Drain Diode Forward Voltage



Fig. 8 - Maximum Safe Operating Area



Fig. 9 - Maximum Drain Current vs. Case Temperature

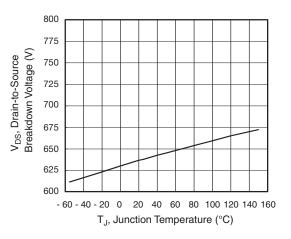


Fig. 10 - Temperature vs. Drain-to-Source Voltage

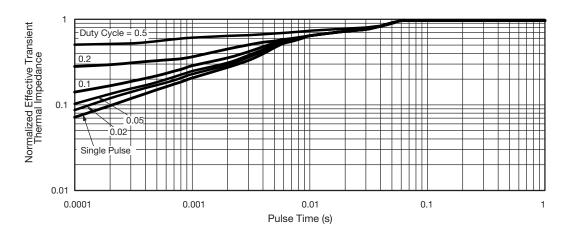


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



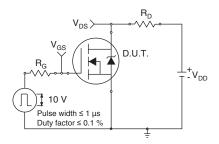


Fig. 12 - Switching Time Test Circuit

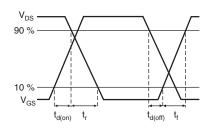


Fig. 13 - Switching Time Waveforms

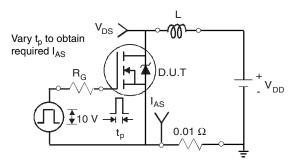


Fig. 14 - Unclamped Inductive Test Circuit

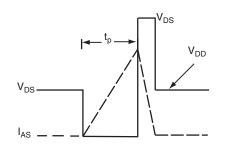


Fig. 15 - Unclamped Inductive Waveforms

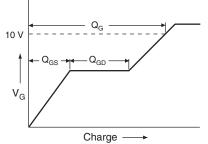


Fig. 16 - Basic Gate Charge Waveform

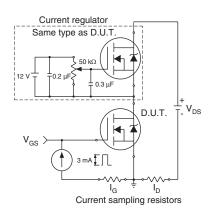
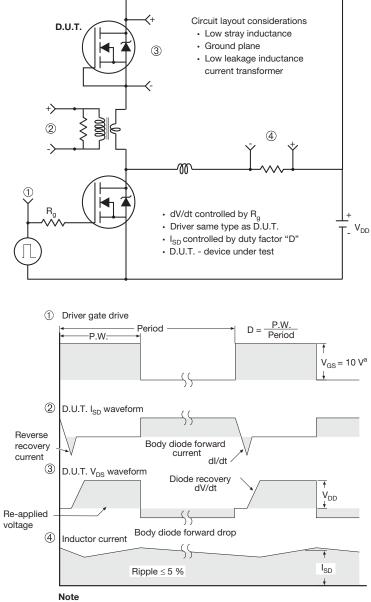


Fig. 17 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit

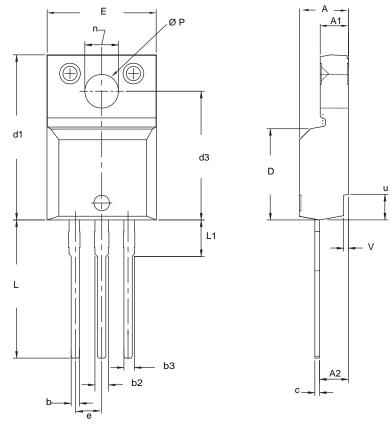


a.  $V_{GS} = 5 V$  for logic level devices

Fig. 18 - For N-Channel



## **TO-220 FULLPAK (HIGH VOLTAGE)**



	MILLI	METERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100	BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØP	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

#### Notes

**Notes** 1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet  $C_{pk} > 1.33$ . 4. All dimensions include burrs and plating thickness. 5. No chipping or package damage.



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